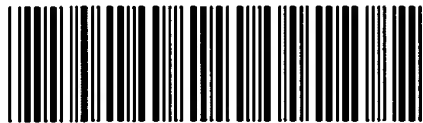


**Search Notes**

Application/Control No.

10/605,203

Examiner

Ernest F. Karlsen

Applicant(s)/Patent under  
Reexamination

FLEISCHMAN, THOMAS J.

Art Unit

2829

**SEARCHED**

Class	Subclass	Date	Examiner
324	158.1 754 765	2/1/2005	E.F.K.
714	700 724	2/1/2005	E.F.K.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
324	158.1 765	2/5/2005	E.F.K.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
time same delay same errors and test and semiconductor		
time adj delay adj error\$	2/1/2005	E.F.K.
calibrat\$ same (time or timing) same test		